Issue Classification



10811973

Examiner

Sandvik, Ben P

Applicant(s)/Patent	Under Reexami	nation
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NOZAWA ET AL.

Art Unit

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ORIGINAL						INTERNATIONAL CLASSIFICATION									
CLASS SL			UBCLASS	CLAIMED			LAIMED	NON-CLAIMED				AIMED			
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CROSS REFERENCE(S)			· -												
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Sandvik, Ben P (Assistant Examiner) (Date)											Total Claims Allowed:				
(Legal Instruments (Date)			(Primary	Evan Pert (Primary Examiner) (Date) (Date)						0.0	O.G. Print Claim(s) O.G. Print Figure				

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